Sister & Matsil, L L.P. 9727329218 3/9

In the Specification:

10/08/2003 02:47 PM, . . .

Under the heading "Brief Description of the Drawings" on page 5, beginning at line 19, please revise that paragraph to read as follows:

-FIG. 2 is a sehematic FIGs. 2a - 2e (collectively FIG. 2) are schematics of the nondestructive method of measuring recess depth of a wafer utilizing a solvent in accordance with the invention process.--